SEP 2 2 2003 AND TRADEMARK

IBM Docket No. FIS920030024US1

Date of Deposit: September 18, 2003

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addressed to Commissioner for Patents in accordance with 37 CFR Sec. 1.8(a) on the date indicated above.

K.CINO-MARS

Teri McDonald

Name of Person Transmitting Paper and Fee

In the United States Patent and Trademark Office

Date: September 18, 2003

In re Application William Wille et al.

Filed: June 24, 2003

of:

For: METHOD FOR FORMING DAMASCENE STRUCTURE

UTILIZING PLANARIZING MATERIAL COUPLED WITH

DIFFUSION BARRIER MATERIAL

Serial Number: 1

10/604,056

Art Unit:

Examiner:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. § 1.56, and further pursuant to the provisions of 37 C.F.R. §§ 1.97 and 1.98, Applicants hereby respectfully submit copies of the prior publications as listed on Form PTO-1449, attached hereto. Applicants also hereby submit a copy of the following pending U.S. patent application:

IBM Dock t No. FIS920030024US1

Ser. No.: 09/256, 034

Filing Date: February 23, 1999 Attorney Docket No.: YO998-056 Inventors: M. Angelopoulos et al.

Title: Multilayered Resist System Using Tuned Polymer Films as Underlayers

and Methods of Fabrication Thereof

In citing these documents, no representation is made nor intended as to the pertinency or non-pertinency of the art, that better art than listed is not available, or that other art is not applicable.

Pursuant to 37 C.F.R. §§ 1.97(b), no fee is believed to be due for this submission. If any fees are required, however, the Commissioner is hereby authorized to charge such fees to Deposit Account No. 09-0458.

Respectfully Submitted,

Margaret A. Pepper *
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		Docket Number (Optional)	Application Number	
SIPES.		FIS920030024US1	10/604,056	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		Applicant(s) William Wille, et al.		
SEP 2 2 2003 2		Filing Date 6/24/03	Group Art Unit	
EXAMINER TRIADENT	OTHER DOCUMENTS (Including Author, Title	e, Date, Pertinent Pages, Etc.)		
WAY DES	"A High Performance 0.13 um C pper BEOL Techn logy with Low-K Dielectric" R.D. Goldblatt, et al. Proceedings of the IEEE 2000 International Interconnect Technology Conference, 5-7 June, 2000, pp.261-263.			
	"A Manufacturable Copper/Low-k SiOC/SiCN Process Technology for 90nm-node High Performance eDRAM", K. Higashi, et al., Proceedings of the IEEE 2002 International Interconnect Technology Conference, 3-5 June 2002, pp. 15-17.			
•	"A High Resolution 248 nm Bilayer Resist" Qinghuang Lin, et al., Proc. SPIE - Int. Soc. Opt. Eng. (USA), vol. 3678, pt. 1-2, pp. 241-50.			
	"Surface treatment validation of inorganic BARC on 0.25 um Non Volatile Memory technology", Y. Trouilleret al. Microelectronic Engineering 46 (1999), pp. 47-50.			
	"Effects of Crosslinking Agent on Lithographic Pe Qinghuang Lin, et al. Proc. SPIE - Int. Soc. Opt.	erformance of Negative-Tone Resists I Eng. (USA), vol 3049, pp. 974-87.	Based on Poly (p-hydroxystyrene)",	
	Patent Application, Serial Number 09/256 Entitled Multilayered Resist System Usin Fabrication Thereof.	nt Application, Serial Number 09/256,034, dated 2/23/99, Inventors M. Angelopoulos, et al. Lied Multilayered Resist System Using Tuned Polymer Films as Underlayers and Methods of Loation Thereof.		
EXAMINER		DATE CONSIDERED		
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not				